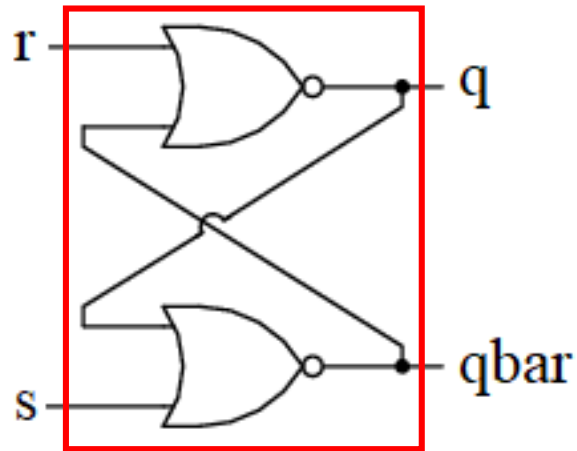


Synchronous Circuits Timing Analysis

©Hanan Ribo

NOR based SR Latch



```

LIBRARY ieee;
USE ieee.std_logic_1164.all;

-----

ENTITY SRlatch IS
    PORT (  s, r: IN std_logic;
           q, qbar: BUFFER std_logic);
END SRlatch;

-----

ARCHITECTURE dataflow OF SRlatch IS
BEGIN

    q <= not(r or qbar);
    qbar <= not(s or q);

END dataflow;
    
```

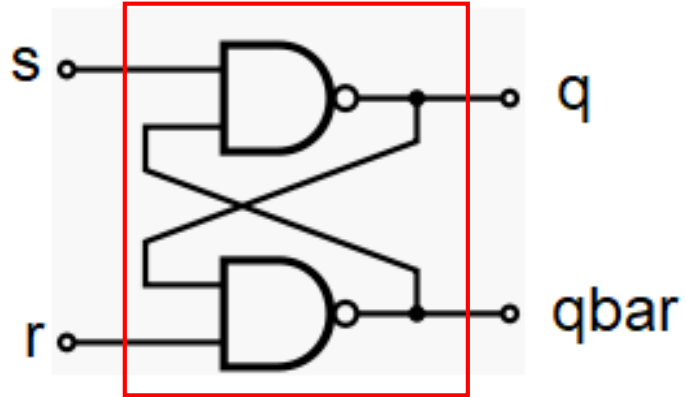
s	r	q	qbar
0	0	q	qbar
0	1	0	1
1	0	1	0
1	1	0	0

1-bit Memory=previous state (there are two possible different stable states)

Only a single stable state

Invalid input, causes a race condition when the input changes in the same time from s=r='1' to s=r='0' (there are two possible different stable states)

NAND based SR Latch



```
LIBRARY ieee;
USE ieee.std_logic_1164.all;

--
ENTITY SRlatch IS
    PORT ( s, r: IN std_logic;
          q, qbar: BUFFER std_logic);
END SRlatch;

--
ARCHITECTURE dataflow OF SRlatch IS
BEGIN

    q <= not (s and qbar);
    qbar <= not (r and q);

END dataflow;
```

s	r	q	qbar
0	0	1	1
0	1	1	0
1	0	0	1
1	1	q	qbar

Invalid input, causes a race condition when the input changes in the same time from $s=r=0$ to $s=r=1$ (there are two possible different stable states)

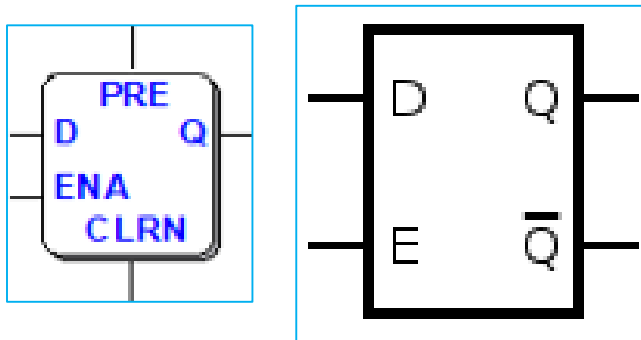
Only a single stable state

1-bit Memory=previous state (there are two possible different stable states)

Gated D-Latch

In order to get rid from race condition (to get zero probability) in SR Latch we need to modify it to a structure called **Gated D-Latch** structure.

Output

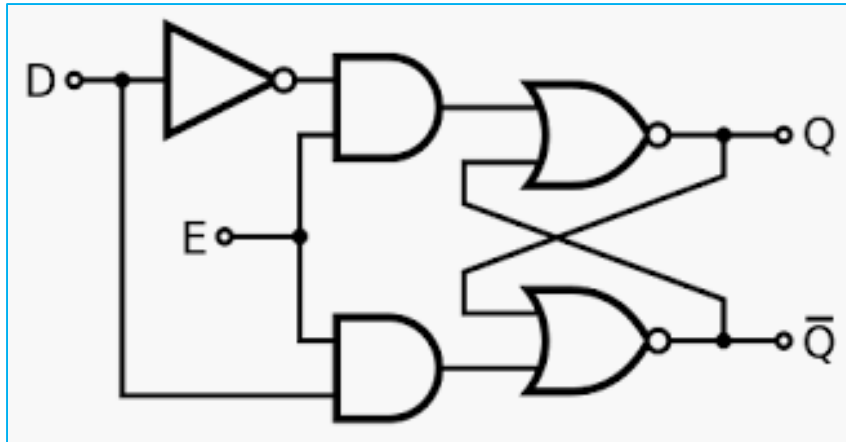


Symbol for a gated D latch

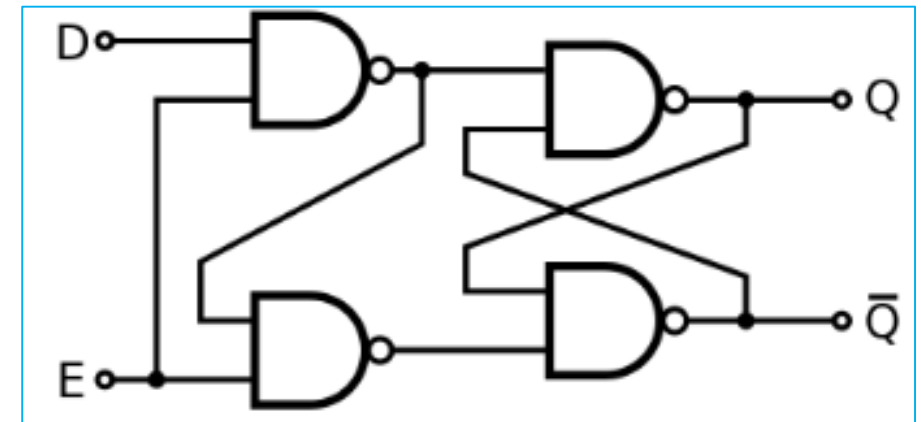
1-bit Memory=previous state

Write operation

E=Enable	D=Data	Q	Qbar
0	x=don't care	Q	Qbar
1	0	0	1
1	1	1	0



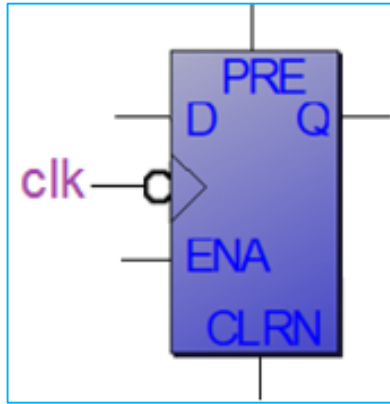
A gated D latch based on an SR NOR latch



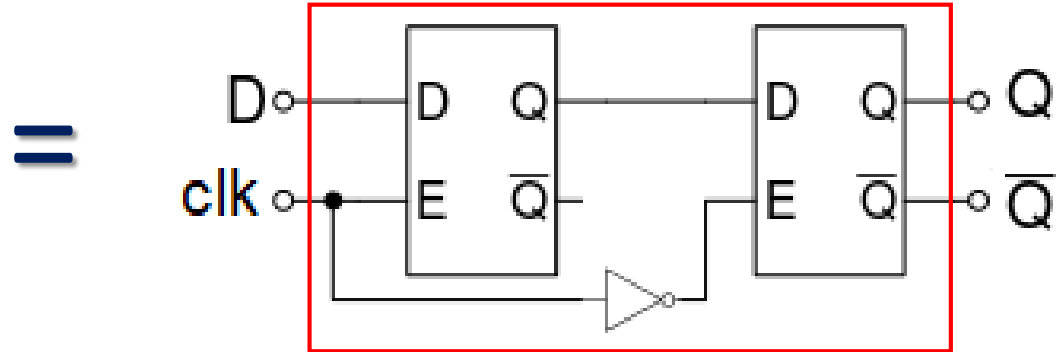
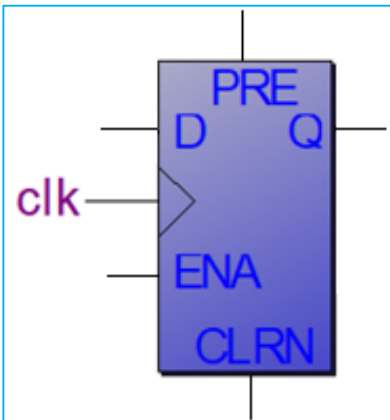
A gated D latch based on an SR NAND latch

D Flip-Flop = DFF

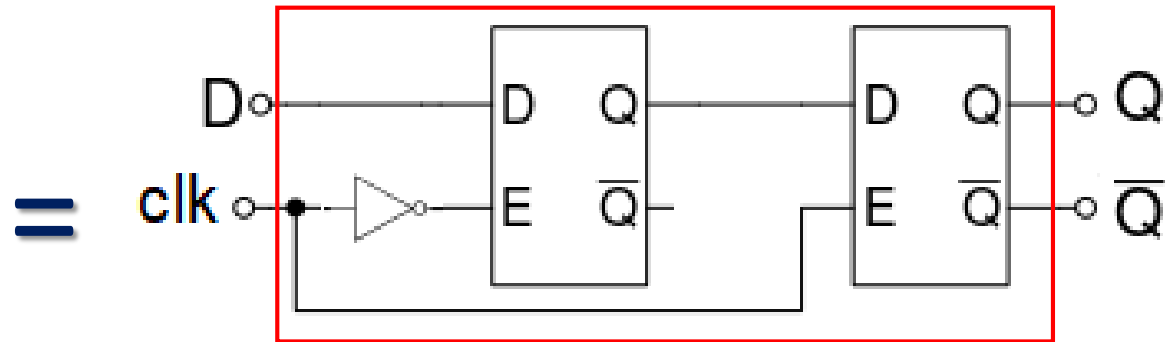
In order to sample the input data at a single point in time (positive or negative edge trigger) we need to use rising/falling derivator structure.



Symbol for a DFF



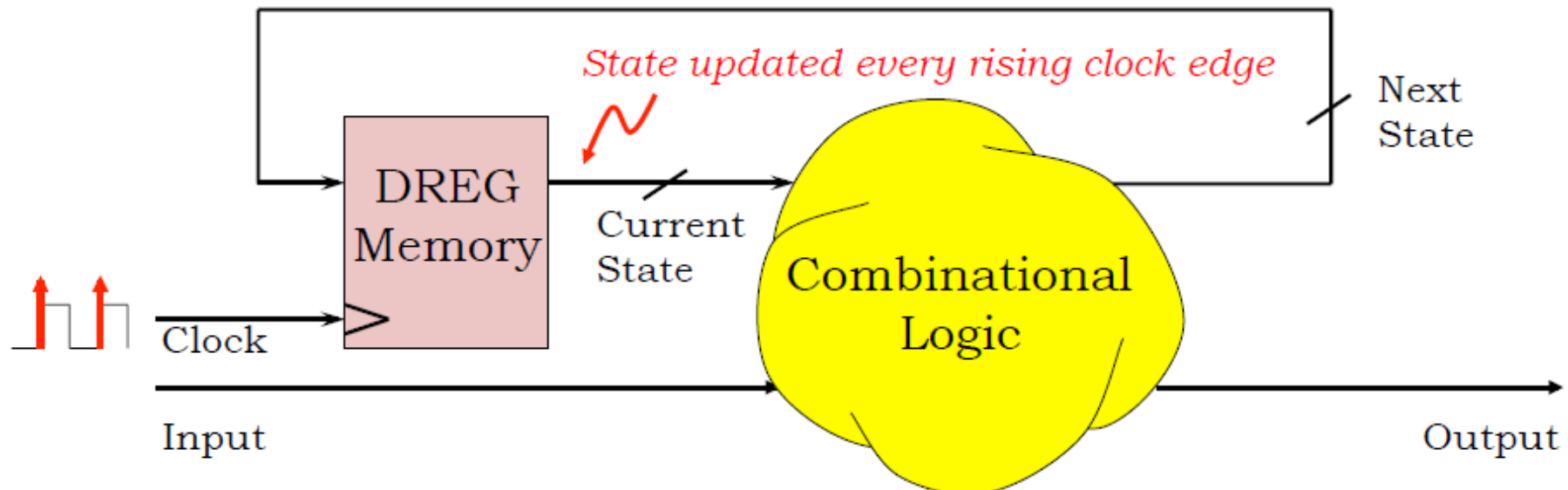
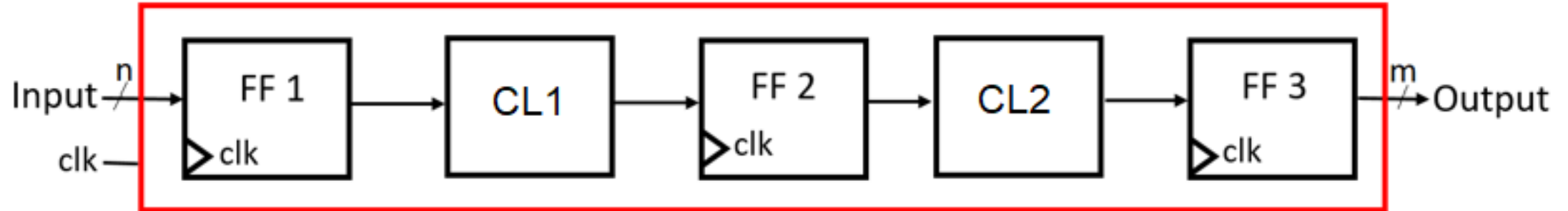
Negative edge DFF



Positive edge DFF

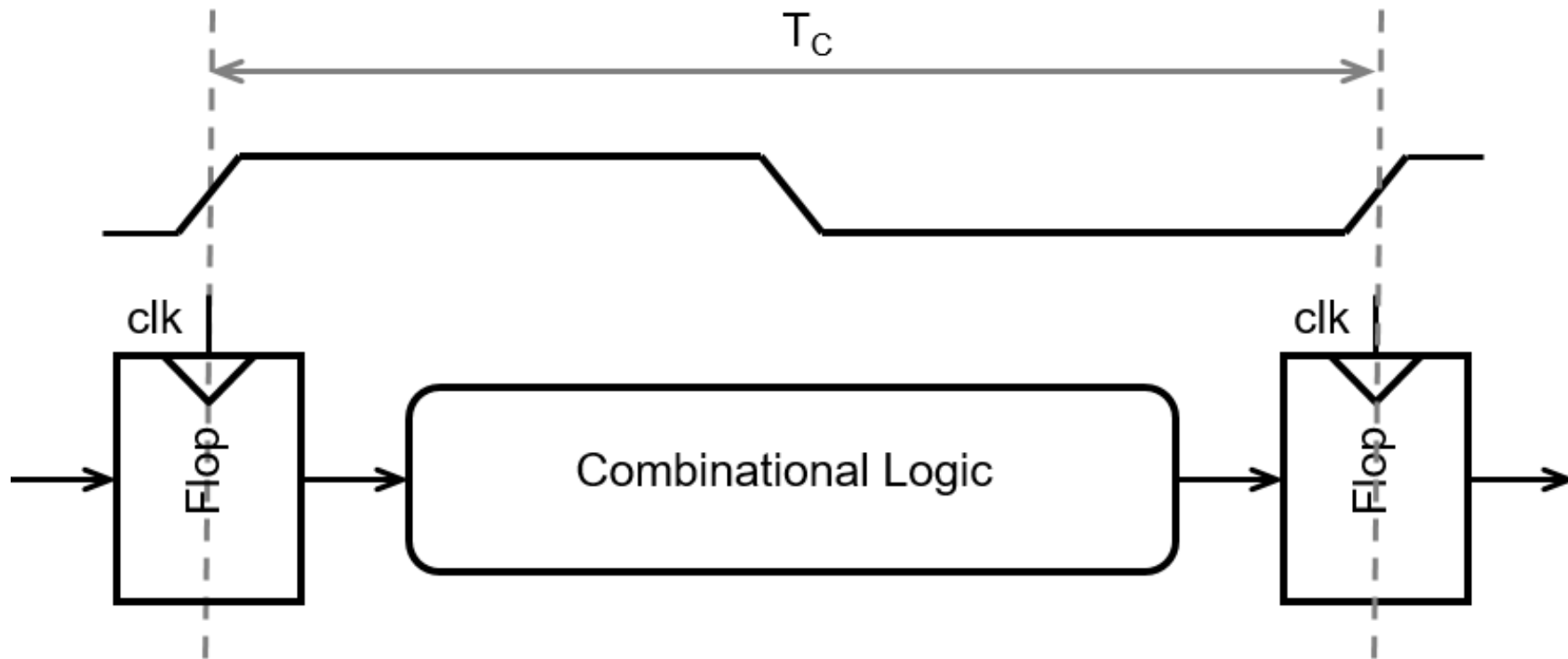
Dynamic Discipline Obedience - Motivation

The output of each combinational logic path between two registers must be steady before each clock's rising edge.

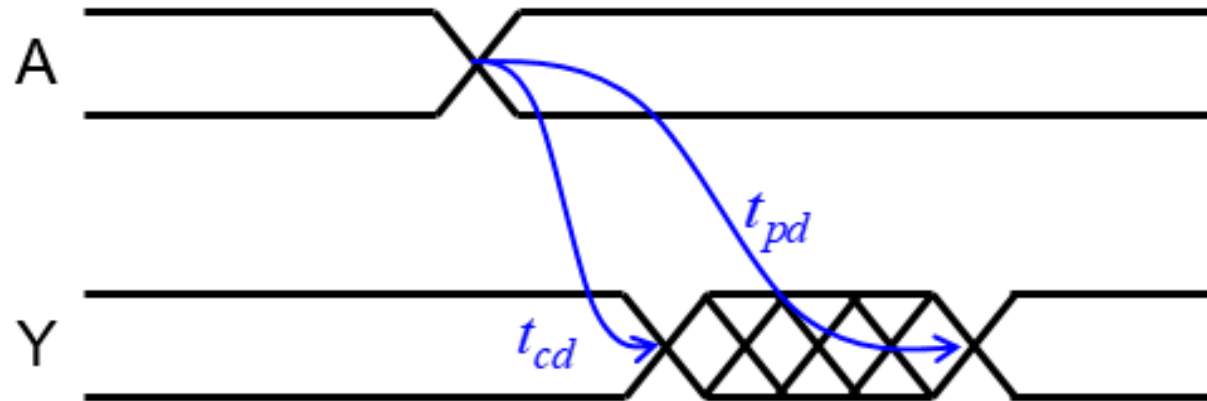
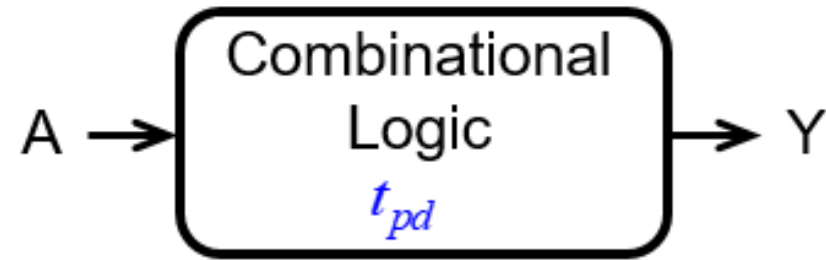


Synchronous Data Movement

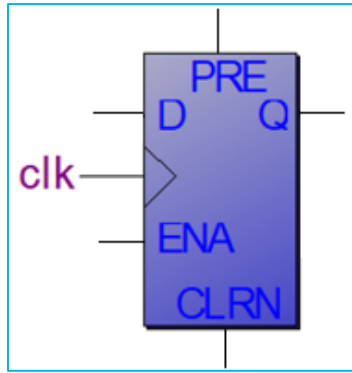
A single flip-flop is used on each cycle boundary. Data advance from one cycle to the next on each clock rising edge.



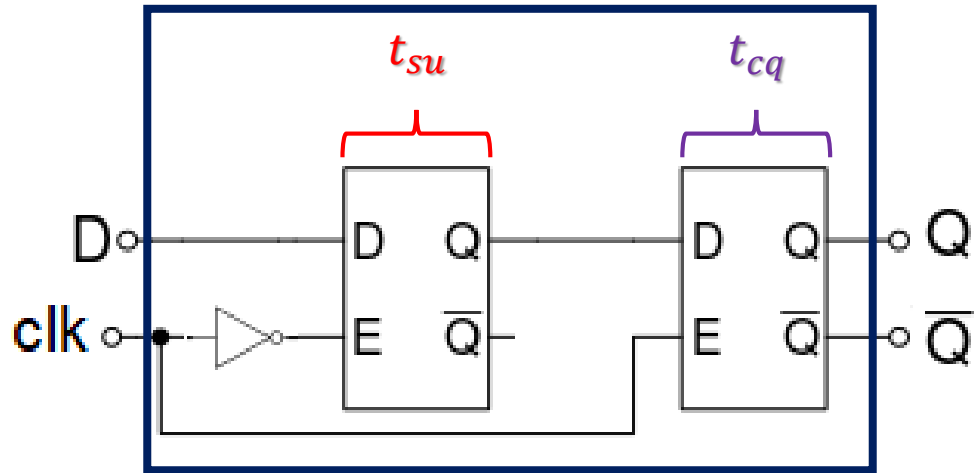
Combinational timing analysis



DFF timing analysis



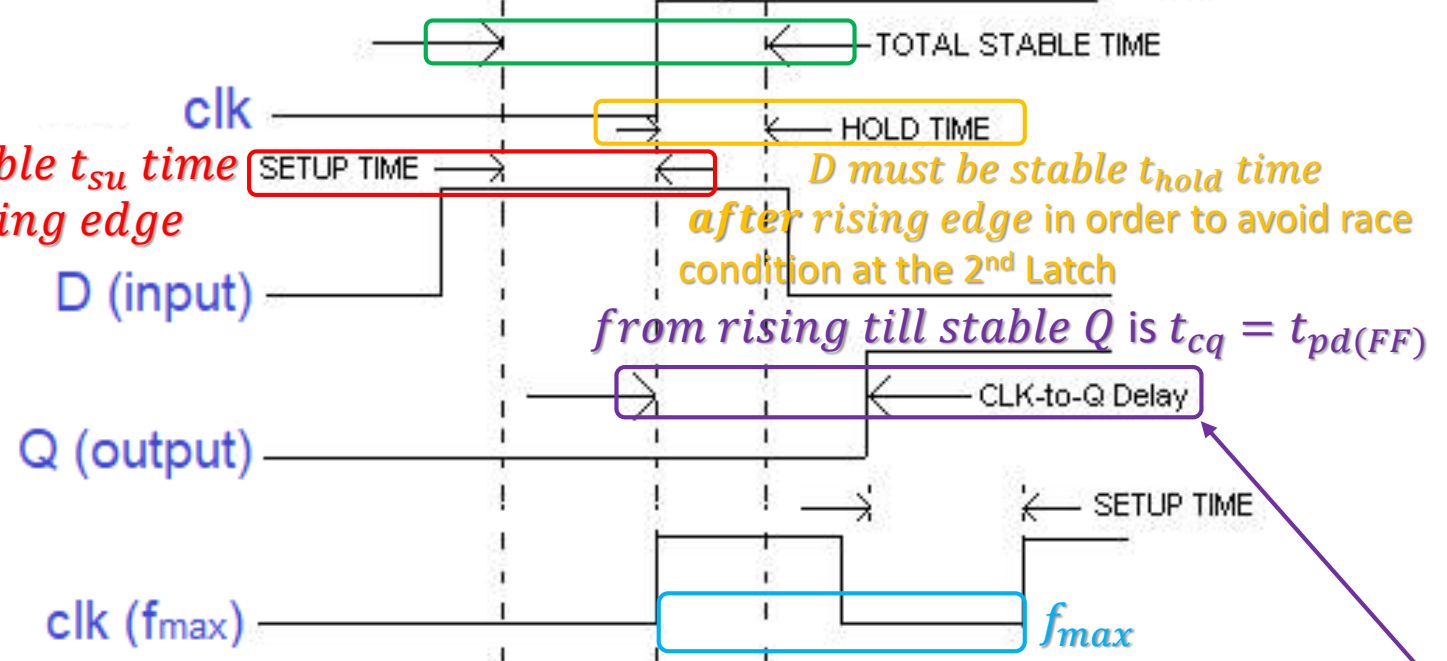
Symbol for a DFF



Positive edge DFF

D must be stable t_{su} time before rising edge

Aperture time (*D must not change in this region*) = $t_{su} + t_{hold}$

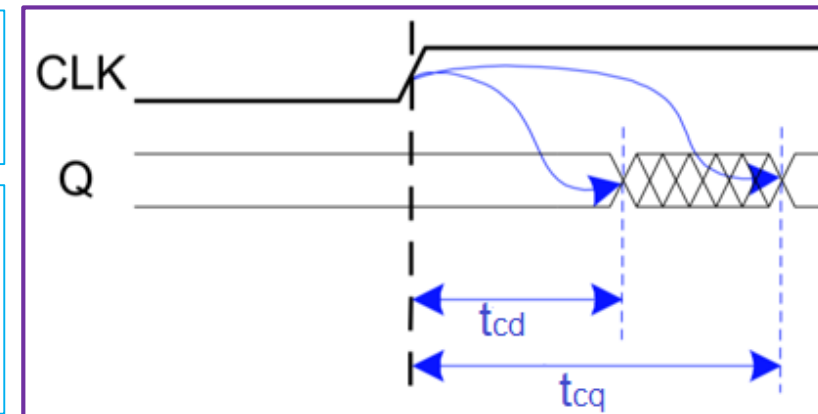


HW requirement:

$$t_{su} < t_{hold} < t_{cd} < t_{cq}$$

$$T_{min} = t_{cq} + t_{su}$$

$$f_{max} = \frac{1}{T_{min}} = \frac{1}{t_{cq} + t_{su}}$$



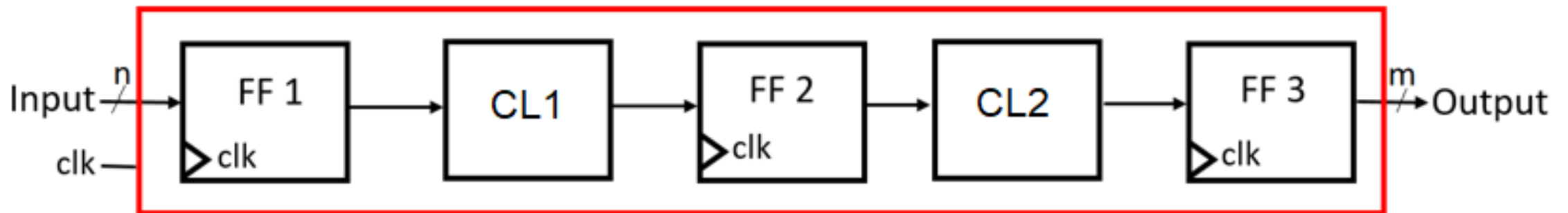
DFF Timing recap

- $t_{cq} = t_{pd(FF)}$: time after clock change that the output is guaranteed to be stable (propagation delay).
- t_{su} : time before clock edge, data must be stable (Setup time)
- t_{hold} : time after clock edge data must be stable (Hold time)
- $t_a = t_{su} + t_{hold}$: time around clock edge data must be stable (Aperture time)
- t_{cd} : time after clock edge that Q is stable by the previous value (Continuation delay)
- $t_{cq} - t_{cd}$: time after clock edge that Q might be unstable (Contamination delay)

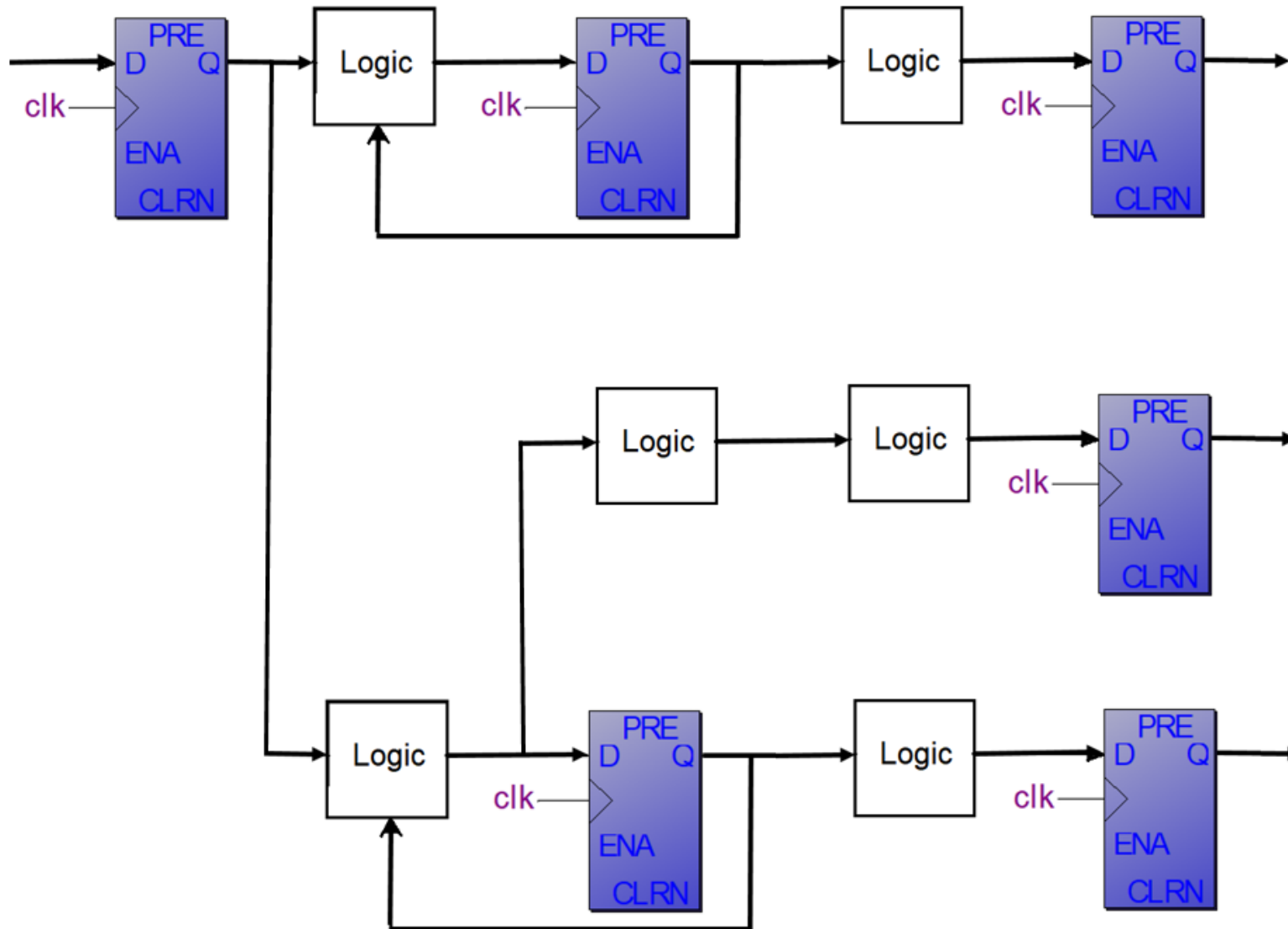
Performance Measurement f_{max}

High Level System Description

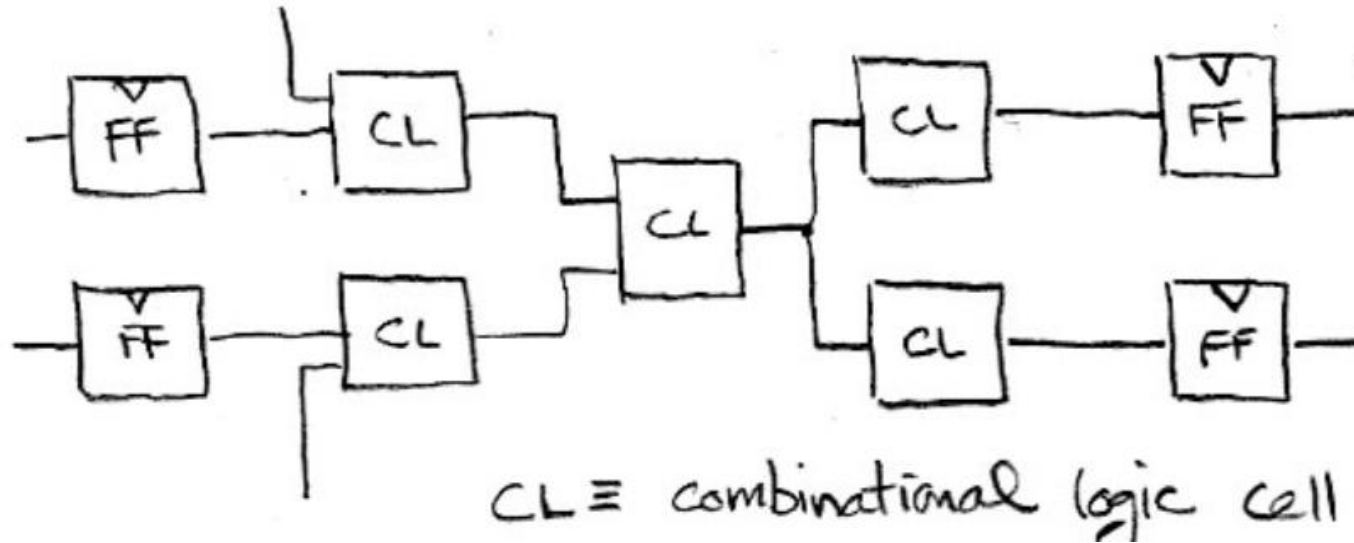
- The most common mistake is to start HDL coding before describing the required digital system in high level of RTL form.
- In RTL system description it becomes clear what are the system's combinational and synchronous subunits.
- Any digital logic system can be disassembled to Combinational Logic blocks chained to FFs (registers) .



RTL design - example

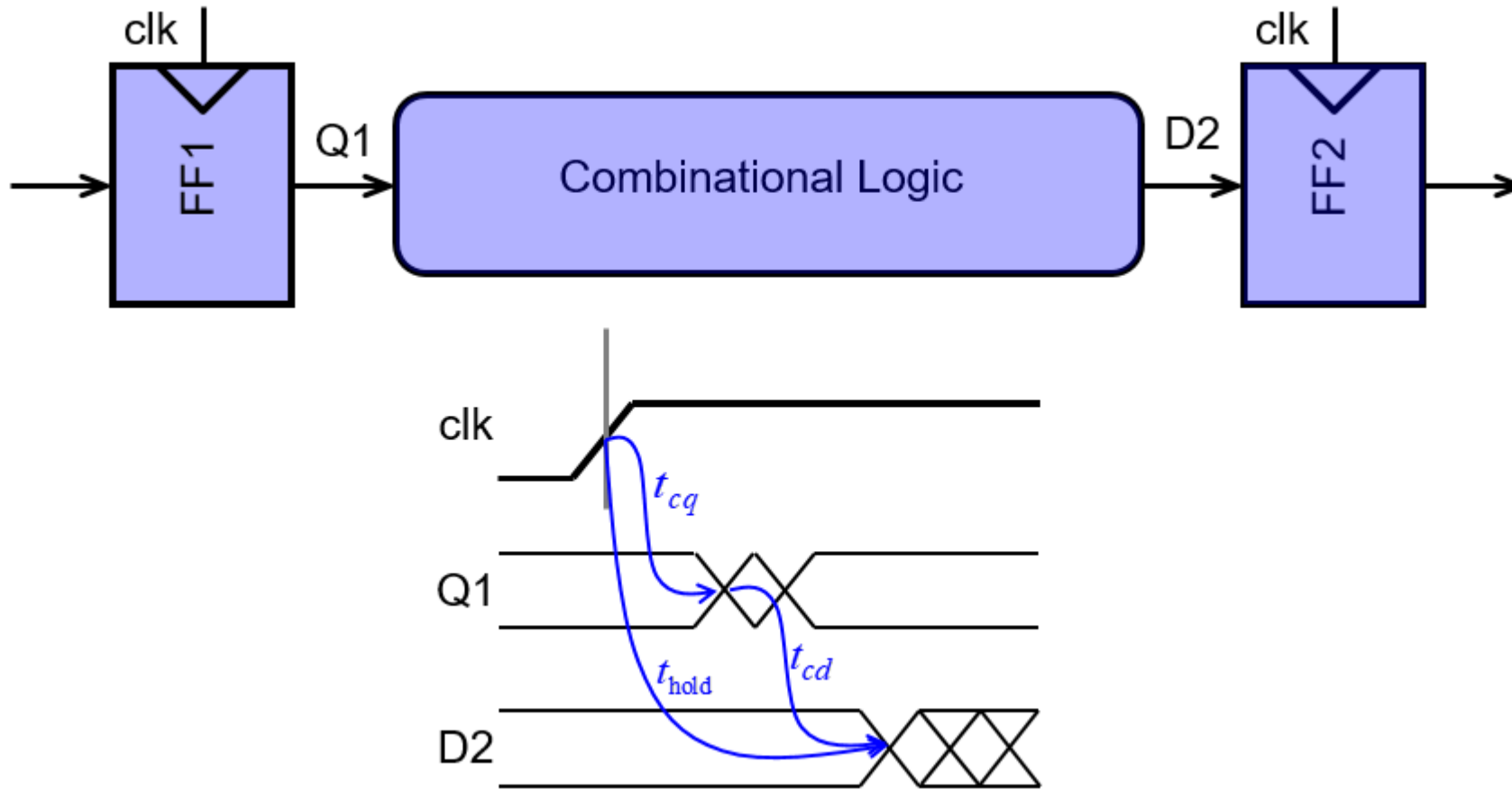


Components of Path Delay



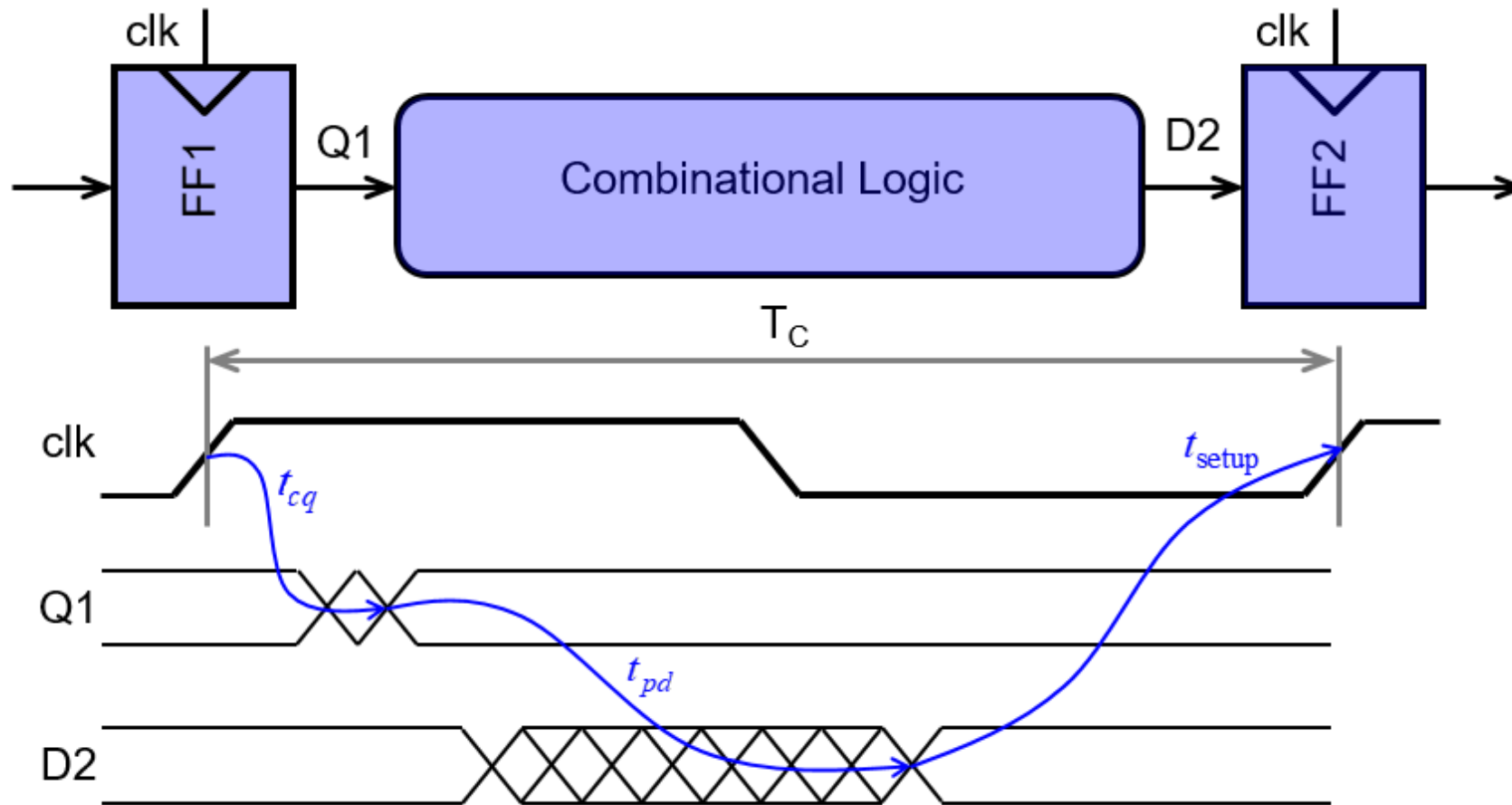
1. # of levels of logic
2. Internal cell delay
3. wire delay
4. cell input capacitance
5. cell fan-out
6. cell output drive strength

Timing Delay Constraints - t_{hold} condition



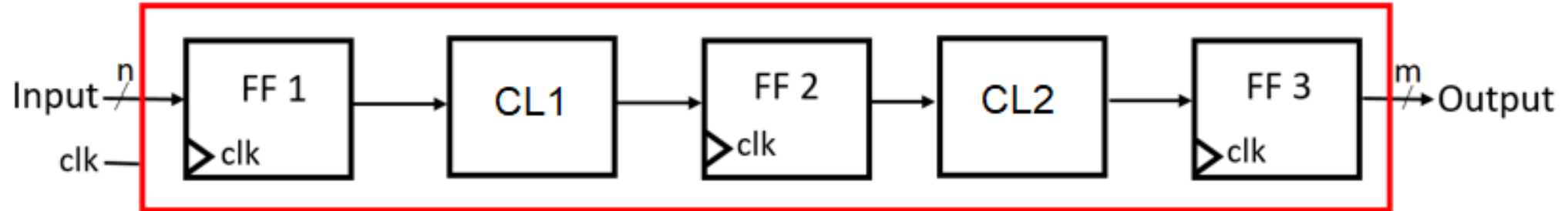
$$t_{cq} + t_{cd} \geq t_{hold} \Rightarrow t_{cd} \geq t_{hold} - t_{cq}$$

Timing Delay Constraints - t_{setup} condition



$$T_{clk} \geq t_{cq} + t_{pd(CL)} + t_{setup} \rightarrow t_{pd(CL)} \leq T_{clk} - \underbrace{(t_{setup} + t_{cq})}_{\text{sequencing overhead}}$$

f_{max} calculation – dynamic discipline Obedience



1. Notations:

- Each CL_i has its own $t_{pd}(CL_i)$
- We assume same technology for all FFs, means same $t_{cq}, t_{cd}, t_{su}, t_{hold}$

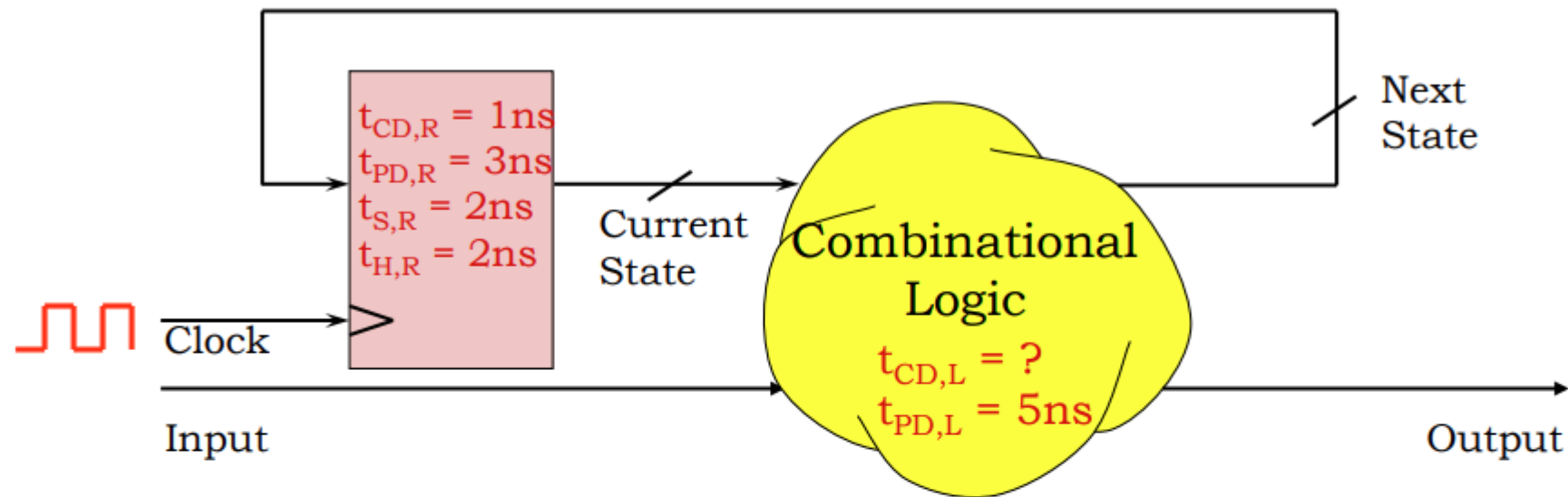
2. In order to get general expression for f_{max} , let's start with the timing condition between the path FF1 to FF2:

- FF2 setup condition: $t_{cq}(FF1) + t_{pd}(CL1) + t_{su}(FF2) \leq T_{clk}$
- FF2 hold condition: $t_{cd}(FF1) + t_{pd}(CL1) \geq t_{hold}(FF2)$

3. General expression for f_{max} : Critical Path - we strive in our design for balanced CL paths

- Setup condition: $t_{cq} + \max_i \{t_{pd}(CL_i)\} + t_{su} = T_{min} \rightarrow f_{max} = \frac{1}{T_{min}}$
- Hold condition: $t_{cd} + \min_i \{t_{pd}(CL_i)\} \geq t_{hold}$

Sequential Circuit Timing



Questions:

- Constraints on t_{CD} for the logic?
- Minimum clock period?
- Setup, Hold times for Inputs?

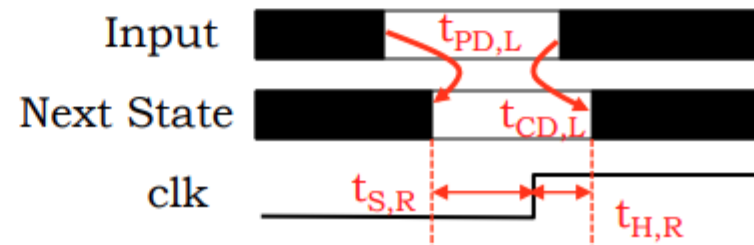
$$t_{S,INPUT} = t_{PD,L} + t_{S,R} = 7 \text{ nS}$$

$$t_{H,INPUT} = t_{H,R} - t_{CD,L} = 1 \text{ nS}$$

$$t_{CD,R} (1 \text{ ns}) + t_{CD,L}(?) \geq t_{H,R}(2 \text{ ns})$$

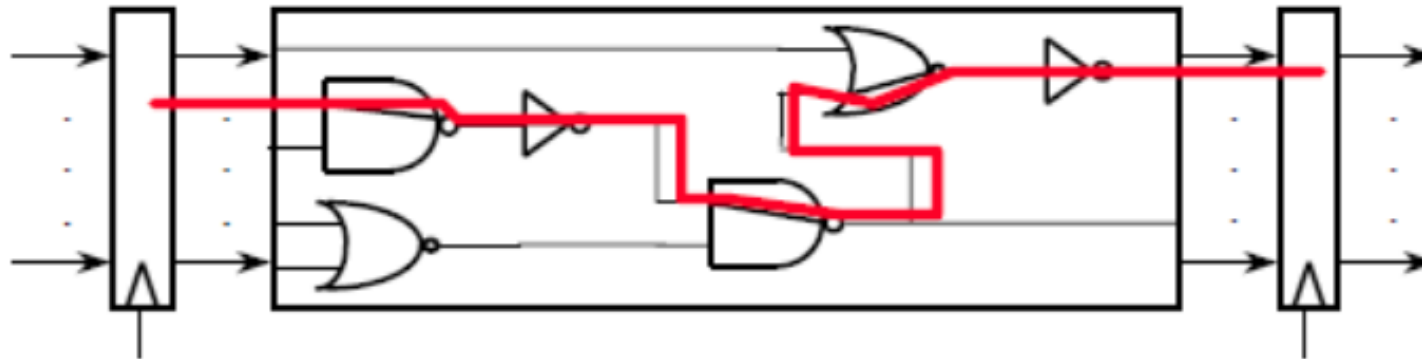
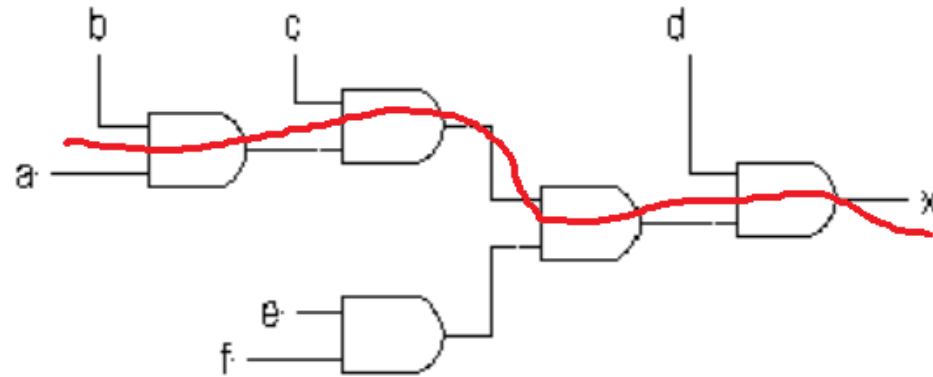
$$t_{CD,L} \geq 1 \text{ ns}$$

$$t_{CLK} \geq t_{PD,R} + t_{PD,L} + t_{S,R} = 10 \text{ nS}$$



Critical Path

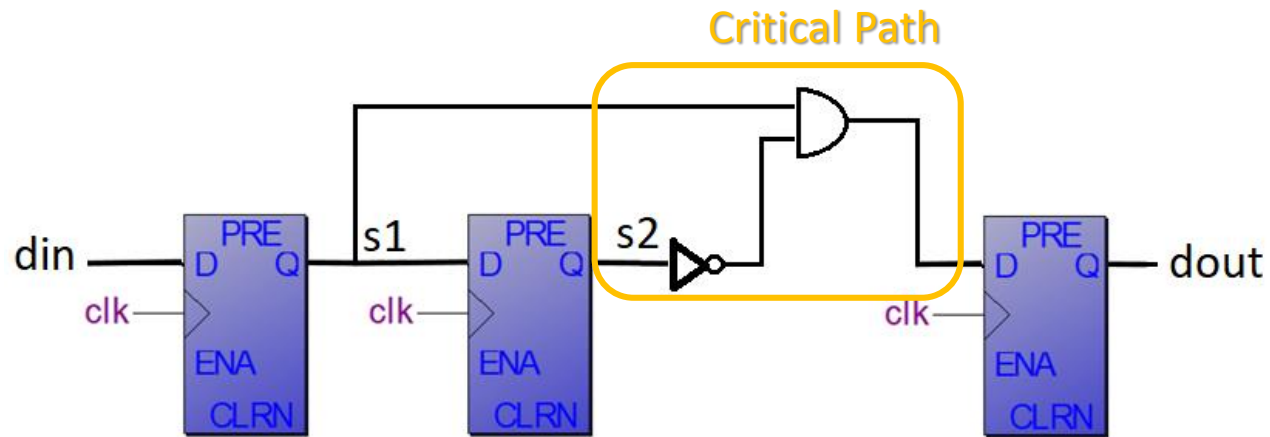
- *Critical Path*: the path in the entire design with the maximum delay.
- This could be from state element to state element, from input to state element, state element to output, from input to output (unregistered paths).
- Example: what is the critical path in this circuit?



f_{max} calculation example

The Given data:

$t_{su} = 200ps, t_{cq} = 300ps, t_{pd(gate)} = 100ps, \text{hold condition exists}$



$$T_{min} = t_{cq} + 2 \cdot t_{pd(gate)} + t_{su} = 700ps \rightarrow f_{max} = \frac{1}{T_{min}} = 1.428GHz$$